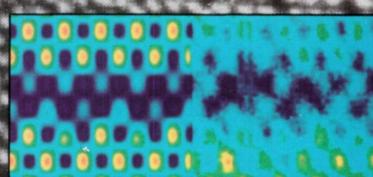


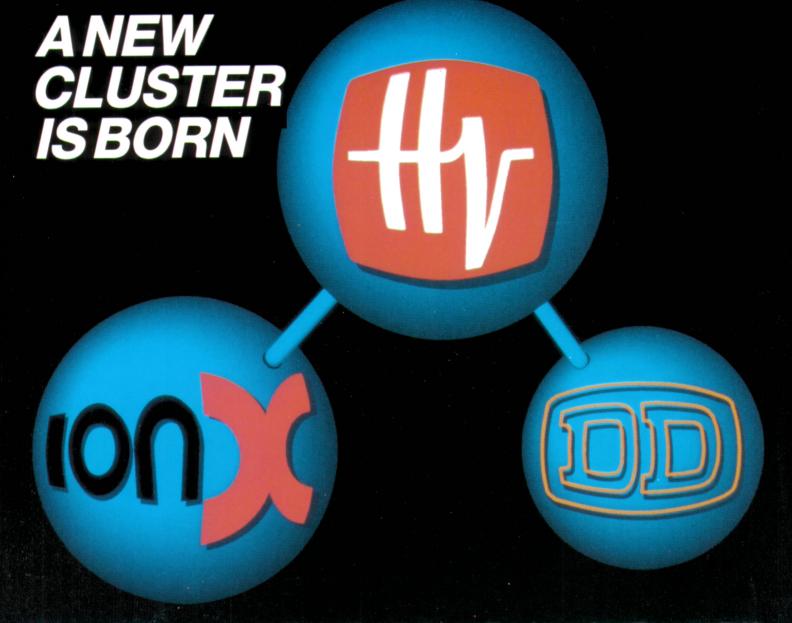
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For further information on this transaction and product literature please contact HVEE in Amersfoort/NL.

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ON THE COVER: The background is an STM image of (7x7) reconstructed Si(111) islands epitaxially grown on a Si(111)-(7x7) substrate at 450°C. It is from Figure 2b in the article by R.J. Hamers on p. 22.

The upper inset shows an artificially colored [110] Z-contrast STEM image of interfacial ordering of an ultrathin (Si₄Ge₈)₂₄ superlattice. The right of the inset shows actual data, the left a simulated image. This image is from Figure 8 in the article by D.E. Jesson and S.J. Pennycook on p. 34.

The lower inset, also artificially colored, is a high resolution TEM micrograph of the interface between NiSi₂ and Si. This metalsemiconductor contact forms a Schottky barrier, and its barrier height and atomic structure have been correlated from an analysis of similar images. This micrograph is from Figure 3b in the article by J.M. Gibson on p. 27.

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